Product data sheet

1. General description

Planar passivated high commutation three quadrant triac in a SOT186A (TO-220F) "full pack" plastic package. This "series E" triac balances the requirements of commutation performance and gate sensitivity and is intended for interfacing with low power drivers including microcontrollers.

2. Features and benefits

- 3Q technology for improved noise immunity
- Direct interfacing with low power drivers and microcontrollers
- Good immunity to false turn-on by dV/dt
- · High commutation capability with sensitive gate
- · High voltage capability
- · Isolated mounting base package
- · Planar passivated for voltage ruggedness and reliability
- · Sensitive gate for easy logic level triggering
- · Triggering in three quadrants only

3. Applications

- Electronic thermostats (heating and cooling)
- High power motor controls e.g. washing machines and vacuum cleaners

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes		Values		Unit
V_{DRM}	repetitive peak off-state voltage				600		V
I _{T(RMS)}	RMS on-state current	full sine wave; $T_h \le 59$ °C; Fig. 1; Fig. 2; Fig. 3			12		А
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5			100		А
		full sine wave; $T_{J(init)}$ = 25 °C; t_p = 16.7 ms			110		Α
T _j	junction temperature				125		°C
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2+ \text{ G+;} $ $T_j = 25 \text{ °C; } Fig. 7$		-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 7$		-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2- \text{ G-;} $ $T_j = 25 \text{ °C; } \underline{\text{Fig. 7}}$		-	-	10	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	15	mA
V _T	on-state voltage	I _T = 15 A; T _j = 25 °C; <u>Fig. 10</u>		-	1.3	1.6	V

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Dynamic	characteristics						
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 402 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		50	-	-	V/µs
00111	rate of change of commutating current	$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 12 \text{ A;}$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s; (snubberless condition); gate open circuit}$		3	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 125 ^{\circ}\text{C}; I_{T(RMS)} = 12 \text{ A};$ $dV_{com}/dt = 10 \text{ V}/\mu\text{s}; gate open circuit}$		6		-	A/ms
		$V_D = 400 \text{ V}; T_j = 125 ^{\circ}\text{C}; I_{T(RMS)} = 12 \text{ A};$ $dV_{com}/dt = 1 \text{ V/}\mu\text{s}; gate open circuit}$		10		-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	T1	main terminal 1	mb	
2	T2	main terminal 2		T2—T1
3	G	gate		G G
mb	n.c	mounting base; isolated		sym051

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
BTA312X-600E	TO220F	BTA312X-600E,127	Tube	50	SOT186A	14-Nov-2013
BTA312X-600E/DG		BTA312X-600E/DGQ	Tube	50	SOT186A (Halogen free)	14-Nov-2013

7. Marking

Table 4. Marking codes

Type number	Marking codes			
	Assembly factory: d	Assembly factory: A		
BTA312X-600E	BTA312X 600E PJdxxxx xx	BTA312X 600E PJAxxxx xx		
BTA312X-600E/DG	BTA312X 600EDG PJdxxxx xx	BTA312X 600EDG PJAxxxx xx		

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
V_{DRM}	repetitive peak off-state voltage			600	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _h ≤ 59 °C; <u>Fig. 1; Fig. 2; Fig. 3</u>		12	А
I _{TSM}	non-repetitive peak on-state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig 4; Fig 5		100	А
		full sine wave; $T_{j(init)} = 25 ^{\circ}\text{C}$; $t_p = 16.7 \text{ms}$		110	А
l²t	I ² t for fusing	t _p = 10 ms; SIN		50	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 0.2 A		100	A/µs
I _{GM}	peak gate current			2	А
P_GM	peak gate power			5	W
$P_{G(AV)}$	average gate power	over any 20 ms period		0.5	W
T _{stg}	storage temperature			-40 to 150	°C
T _j	junction temperature			125	°C

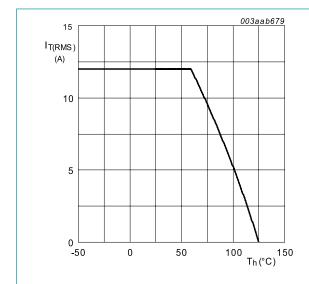
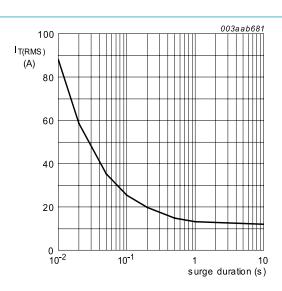
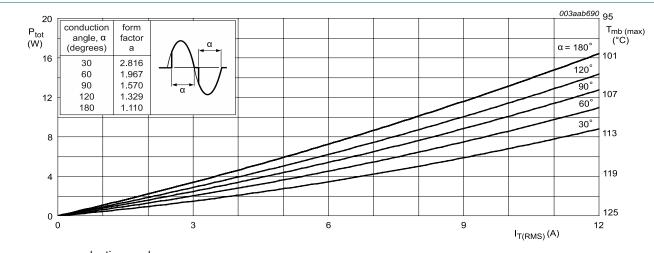


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



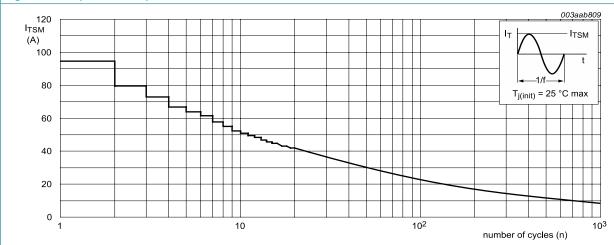
f = 50 Hz; T_{mb} = 59 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values



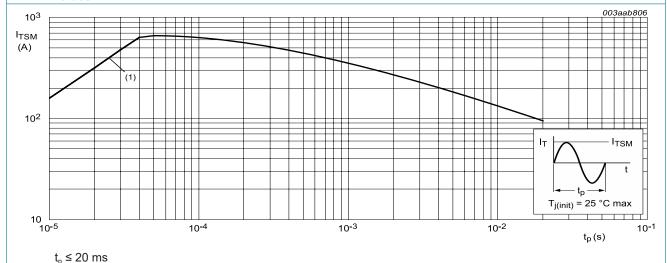
 α = conduction angle

a = form factor = $I_{T(RMS)} / I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum Fig. 4.



 $(1) dI_{T}/dt limit$

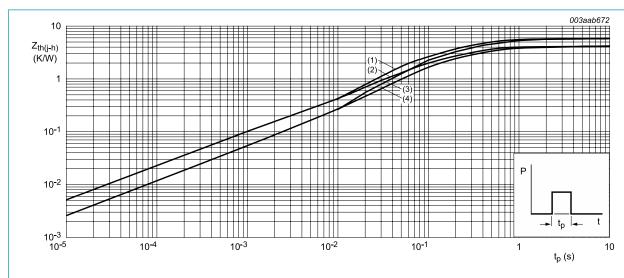
f = 50 Hz

Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-h)}	thermal resistance from junction to heatsink	full cycle or half cycle; with heatsink compound; Fig. 6		-	-	4	K/W
		full cycle or half cycle; without heatsink compound; Fig. 6		-	-	5.5	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	in free air		-	55	-	K/W



- (1) Unidirectional (half cycle) without heatsink compound
- (2) Unidirectional (half cycle) with heatsink compound
- (3) Bidirectional (full cycle) without heatsink compound
- (4) Bidirectional (full cycle) with heatsink compound

Fig. 6. Transient thermal impedance from junction to heatsink as a function of pulse duration

10. Isolation characteristics

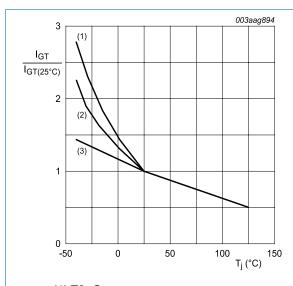
Table 7. Isolation characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
V _{isol(RMS)}	RMS isolation voltage	from all pins to external heatsink; sinusoidal waveform; clean and dust free; $50 \text{ Hz} \le f \le 60 \text{ Hz}$; RH $\le 65 \text{ %}$; T _h = 25 °C		-	-	2500	V
C _{isol}	isolation capacitance	from main terminal 2 to external heatsink; $f = 1 \text{ MHz}$; $T_h = 25 \text{ °C}$		-	10	-	pF

11. Characteristics

Table 8. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics					'	'
l _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G+;$ $T_j = 25 \text{ °C; } Fig. 7$		-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T2 + G-;$ $T_j = 25 \text{ °C; } Fig. 7$		-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; Fig. 7}$		-	-	10	mA
IL	latching current	$V_D = 12 \text{ V; } I_G = 0.1 \text{ A; } T2 + G+;$ $T_j = 25 \text{ °C; } Fig. 8$		-	-	25	mA
		$V_D = 12 \text{ V; } I_G = 0.1 \text{ A; } T2 + G -;$ $T_j = 25 \text{ °C; } Fig. 8$		-	-	30	mA
		$V_D = 12 \text{ V; } I_G = 0.1 \text{ A; T2- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$		-	-	25	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>		-	-	15	mA
V _T	on-state voltage	I _T = 15 A; T _j = 25 °C; <u>Fig. 10</u>		-	1.3	1.6	V
V _{GT} gate trigger voltage	gate trigger voltage	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; } T_j = 25 \text{ °C;}$ Fig. 11		-	0.7	1	V
		$V_D = 400 \text{ V}; I_T = 0.1 \text{ A}; T_j = 150 ^{\circ}\text{C}$		0.25	0.4	-	V
I _D	off-state current	V _D = 600 V; T _j = 125 °C		-	0.1	0.5	mA
Dynamic	characteristics						
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 402 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit		50	-	-	V/µs
dI _{com} /dt	rate of change of commutating current	$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 12 \text{ A};$ $dV_{com}/dt = 20 \text{ V}/\mu\text{s}; \text{ (snubberless condition); gate open circuit}$		3	-	-	A/ms
		$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 12 \text{ A; } dV_{com}/dt = 10 \text{ V/}\mu\text{s; gate open circuit}$		6		-	A/ms
		$V_D = 400 \text{ V; } T_j = 125 \text{ °C; } I_{T(RMS)} = 12 \text{ A;}$ $dV_{com}/dt = 1 \text{ V/}\mu\text{s; gate open circuit}$		10		-	A/ms



- (1) T2- G-
- (2) T2+ G-
- (3) T2+ G+

Fig. 7. Normalized gate trigger current as a function of junction temperature

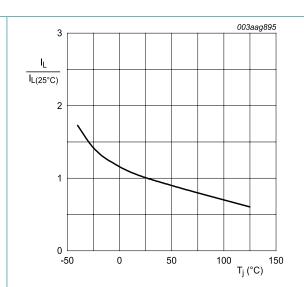


Fig. 8. Normalized latching current as a function of junction temperature

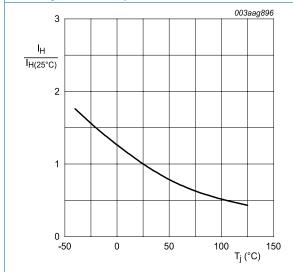
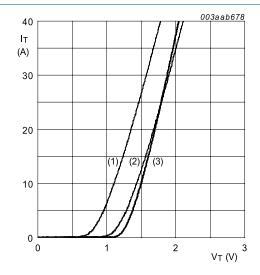


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o = 1.164 \text{ V}; R_s = 0.027 \Omega$

(1) $T_j = 125$ °C; typical values (2) $T_j = 125$ °C; maximum values

(3) $T_j = 25$ °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

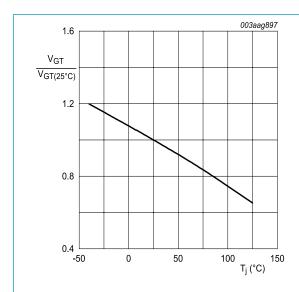
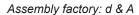
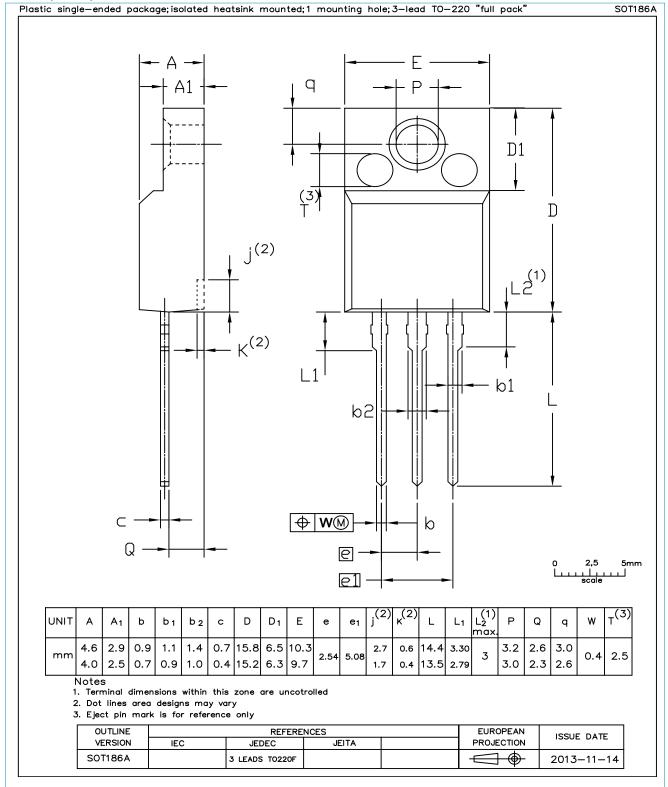


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

12. Package outline





13. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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For more information, please visit: http://www.ween-semi.com
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